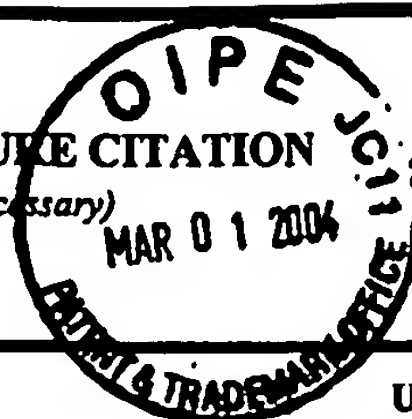


INFORMATION DISCLOSURE CITATION

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Docket Number (Optional)

YOR920020352US1 (16088)

Application Number

10/620,078

Applicant(s)

Bowen Alpern, et al.

Filing Date

July 15, 2003

Group Art Unit

2121 2142

U.S. PATENT DOCUMENTS

| EXAMINER INITIAL | REF | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
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FOREIGN PATENT DOCUMENTS

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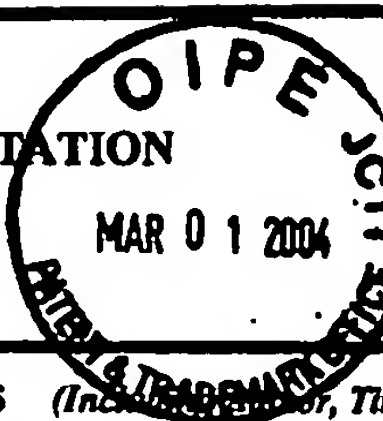
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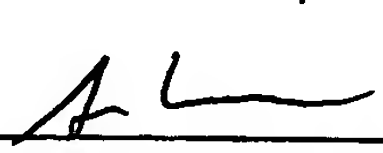
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| INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) | |  | Docket Number (Optional) YOR920020352US1 (16088) | Application Number 10/620,078 |
| | | | Applicant(s) Bowen Alpern, et al | |
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A circular black ink stamp from the Office of the Inspector General, Department of Justice. The text "OFFICE OF THE INSPECTOR GENERAL" is curved along the top inner edge, and "DEPARTMENT OF JUSTICE" is curved along the bottom inner edge. In the center, the date "MAR 01 2004" is stamped. The stamp is partially overlapping a horizontal line and some text at the bottom of the page.

YOR920020352US1 (16088)

10/620,078

Bowen Alpern, et al

July 15, 2003

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